

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 11047572 A	02-1999	Japan	KAMIWANO et al.	
	O	EP 526699 A1	02-1993	European Patent	INOUE, MASAKAZU	
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NON-PATENT DOCUMENTS

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